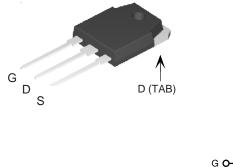


## FS10SM-16-VB Datasheet

# N-Channel 800V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
$V_{DS}$ (V) at $T_J$ max.	850			
R <sub>DS(on)</sub> typ. (Ω) at 25 °C	$V_{GS} = 10 V$	0.40		
Q <sub>g</sub> max. (nC)	88			
Q <sub>gs</sub> (nC)	9			
Q <sub>gd</sub> (nC)	16			
Configuration	Single			





## FEATURES

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Qg)
- Avalanche energy rated (UIS)

### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial
  - Welding
  - Induction heating
  - Motor drives
  - Battery chargers
  - Renewable energy
  - Solar (PV inverters)

<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_C = 25 \text{ °C}$ , unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-source voltage			V <sub>DS</sub>	800	V	
Gate-source voltage			V <sub>GS</sub>	± 30	v	
Continuous drain current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C	- I <sub>D</sub>	11		
		T <sub>C</sub> = 100 °C		8	А	
Pulsed drain current <sup>a</sup>			I <sub>DM</sub>	32		
Linear derating factor				1.4	W/°C	
Single pulse avalanche energy <sup>b</sup>			E <sub>AS</sub>	226	mJ	
Maximum power dissipation			PD	179	W	
Operating junction and storage temperature range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-source voltage slope	T <sub>J</sub> = 125 °C		dV/dt	70	V/ns	
Reverse diode dV/dt <sup>d</sup>			av/at	4.3	v/ns	
Soldering recommendations (peak temperature) <sup>c</sup>	For 10 s			300	°C	

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N-Channel MOSFET

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature

b.  $V_{DD}$  = 140 V, starting  $T_J$  = 25 °C, L = 28.2 mH,  $R_g$  = 25  $\Omega,\,I_{AS}$  = 4.0 A

c. 1.6 mm from case

d.  $I_{SD} \leq I_D, \, dl/dt$  = 100 A/µs, starting  $T_J$  = 25  $^\circ C$ 

HALOGEN

FREE



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum junction-to-ambient	R <sub>thJA</sub>	-	62	°C/W	
Maximum junction-to-case (drain)	R <sub>thJC</sub>	-	0.7	0/₩	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-source breakdown voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = 250 \mu A$		800	-	-	V
V <sub>DS</sub> temperature coefficient	$\Delta V_{DS}/T_{J}$	Referenc	Reference to 25 °C, I <sub>D</sub> = 1 mA		1.1	-	V/°C
Gate-source threshold voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		-	4	V
Gate-source leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 V$		-	-	± 100	nA
		, v	V <sub>GS</sub> = ± 30 V	-	-	± 1	μA
Zeve nete velte se elvele e velt		V <sub>DS</sub> =	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V		-	1	μA
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> = 640 V	$V_{DS} = 640 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 ^{\circ}\text{C}$		-	10	
Drain-source on-state resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	I <sub>D</sub> = 5.5 A	-	0.40	-	Ω
Forward transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 5.5 A		-	4.5	-	S
Dynamic							
Input capacitance	C <sub>iss</sub>	$V_{GS} = 0 V,$		-	1670	-	pF
Output capacitance	C <sub>oss</sub>	,	$V_{\rm DS} = 0.0$ V, $V_{\rm DS} = 100$ V,		68	-	
Reverse transfer capacitance	C <sub>rss</sub>	f = 1 MHz		-	9	-	
Effective output capacitance, energy related <sup>a</sup>	C <sub>o(er)</sub>	$V_{\rm DS}$ = 0 V to 480 V, $V_{\rm GS}$ = 0 V		-	43	-	
Effective output capacitance, time related <sup>b</sup>	C <sub>o(tr)</sub>			-	212	-	
Total gate charge	Qg			-	44	88	
Gate-source charge	Q <sub>gs</sub>	$V_{GS} = 10 V$	$V_{GS} = 10 \text{ V}$ $I_D = 5.5 \text{ A}, V_{DS} = 480 \text{ V}$		9	-	nC
Gate-drain charge	Q <sub>gd</sub>				16	-	
Turn-on delay time	t <sub>d(on)</sub>				18	36	- ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> = 480 V, I <sub>D</sub> = 5.5 A,		-	15	30	
Turn-off delay time	t <sub>d(off)</sub>		$V_{GS} = 10 \text{ V}, \text{ R}_{g} = 9.1 \Omega$		55	110	
Fall time	t <sub>f</sub>	1		-	18	36	
Gate input resistance	Rg	f = 1 MHz, open drain		0.4	0.9	1.8	Ω
Drain-Source Body Diode Characteristic	s	-					
Continuous source-drain diode current	۱ <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	12	
Pulsed diode forward current	I <sub>SM</sub>			-	-	32	A
Diode forward voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 5.5 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse recovery time	t <sub>rr</sub>	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 5.5 \text{ A},$ di/dt = 100 A/µs, V <sub>R</sub> = 25 V		-	345	690	ns
Reverse recovery charge	Q <sub>rr</sub>			-	4.2	8.4	μC
Reverse recovery current	I <sub>RRM</sub>			-	21	-	A

#### Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ 



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

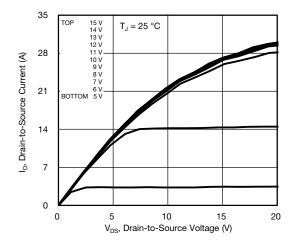


Fig. 1 - Typical Output Characteristics

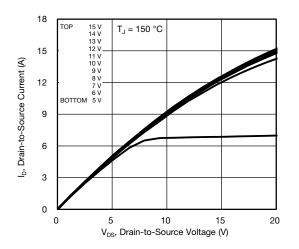
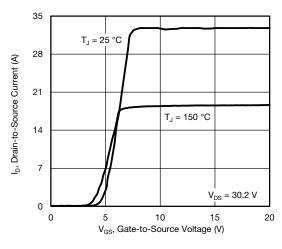
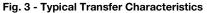


Fig. 2 - Typical Output Characteristics





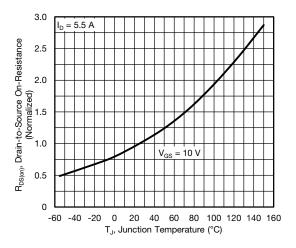


Fig. 4 - Normalized On-Resistance vs. Temperature

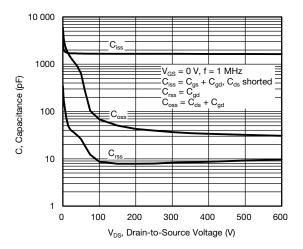


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

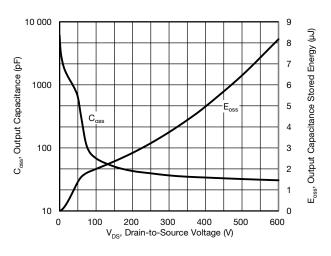


Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$ 



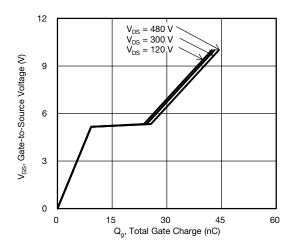


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

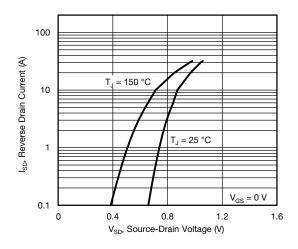


Fig. 8 - Typical Source-Drain Diode Forward Voltage

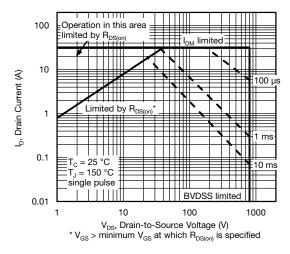


Fig. 9 - Maximum Safe Operating Area

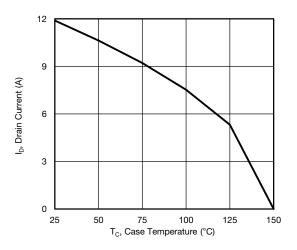


Fig. 10 - Maximum Drain Current vs. Case Temperature

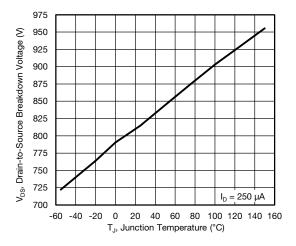


Fig. 11 - Temperature vs. Drain-to-Source Voltage



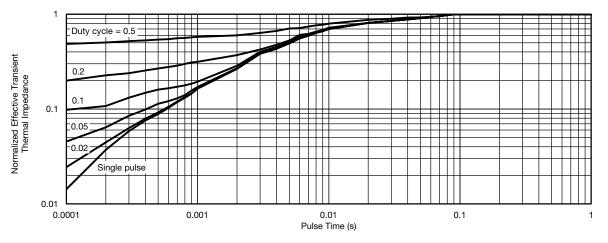


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

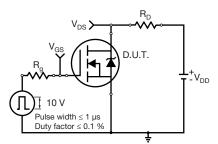


Fig. 13 - Switching Time Test Circuit

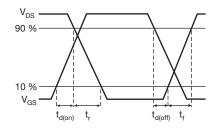


Fig. 14 - Switching Time Waveforms

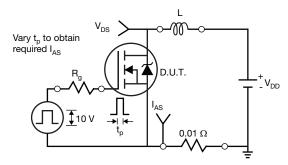


Fig. 15 - Unclamped Inductive Test Circuit

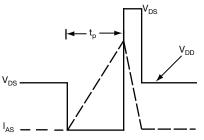


Fig. 16 - Unclamped Inductive Waveforms

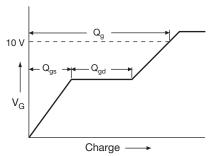


Fig. 17 - Basic Gate Charge Waveform

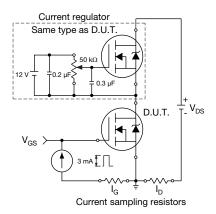


Fig. 18 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

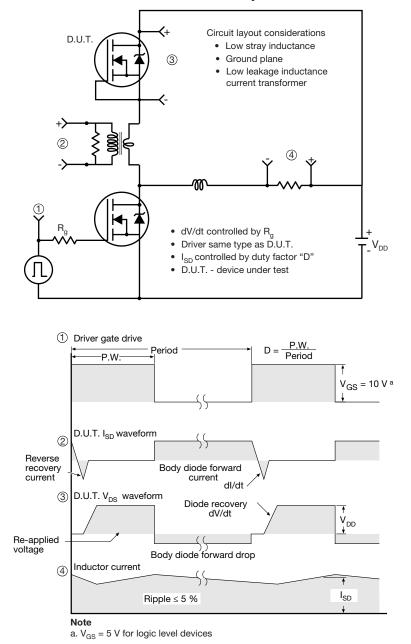
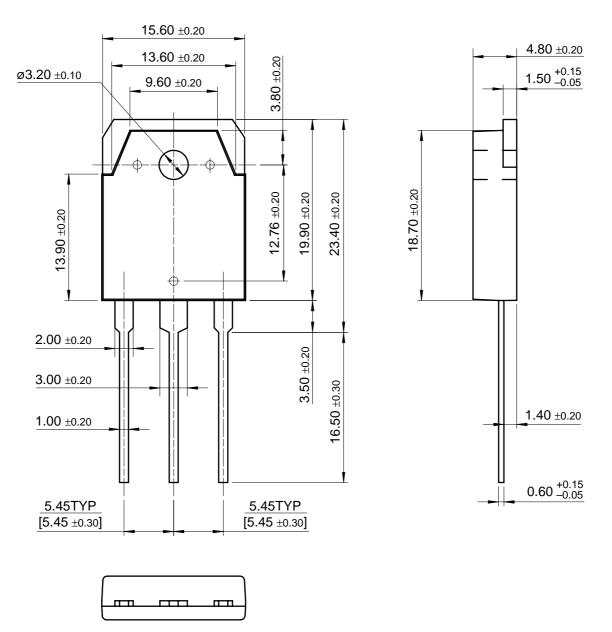


Fig. 19 - For N-Channel



TO-3P





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